Signetics

FAST 74F125, 74F126
Buffers

FAST Products

74F125 Quad Buffer (3-State)
74F126 Quad BUffer (3-State)

Product Specification

FEATURES
- **High Impedance NPN base Inputs for reduced loading (20μA in High and Low states)**

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F125	5.0ns	23mA
74F126	5.0ns	26mA

ORDERING INFORMATION

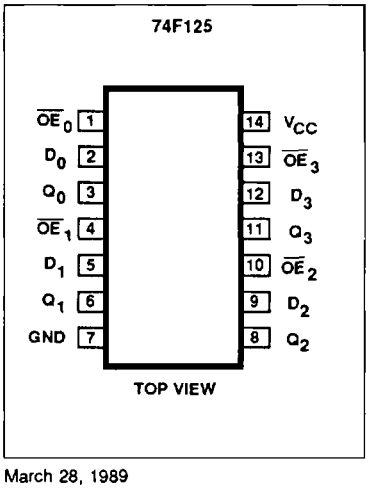
PACKAGES	COMMERCIAL RANGE V_{CC} = 5V±10%; T_A = 0°C to +70°C
14-Pin Plastic DIP	N74F125N, N74F126N
14-Pin Plastic SO	N74F125D, N74F126D

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

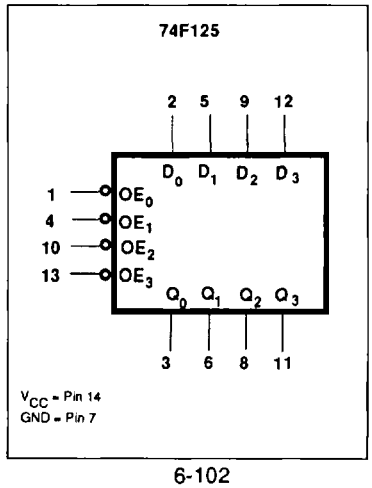
PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D_0-D_3	Data inputs	1.0/0.033	20μA/20μA
$\overline{OE}_0$-$\overline{OE}_3$	Output Enable inputs (active Low), F125	1.0/0.033	20μA/20μA
OE_0-OE_3	Output Enable inputs (active High), F126	1.0/0.033	20μA/20μA
Q_0-Q_3	Data outputs	750/106.7	15mA/64mA

NOTE:
One (1.0) FAST Unit Load is defined as: 20μA in the High state and 0.6mA in the Low state.

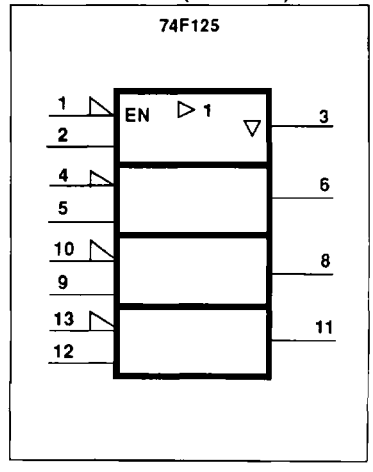
PIN CONFIGURATION



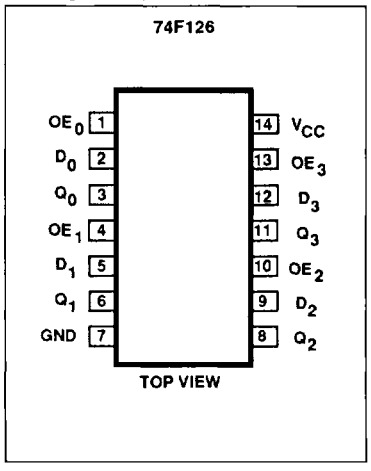
LOGIC SYMBOL



LOGIC SYMBOL(IEEE/IEC)



PIN CONFIGURATION



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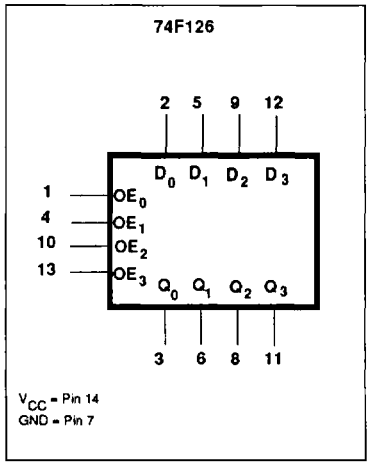

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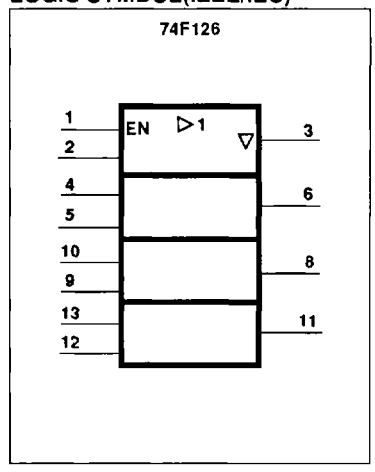
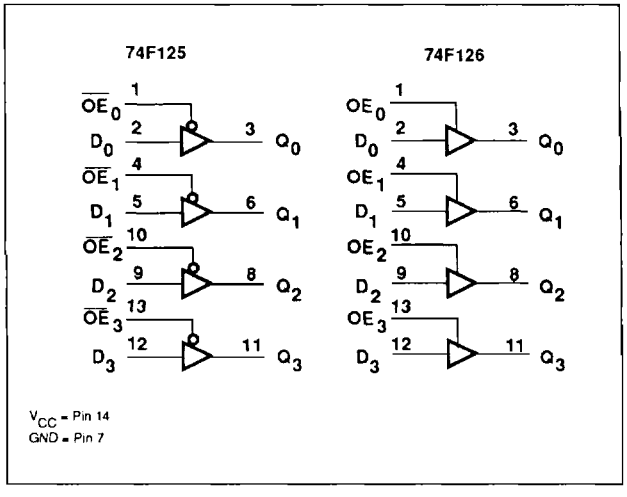


LOGIC DIAGRAM



FUNCTION TABLE, 74F125

INPUTS		OUTPUT
$\overline{OE}_n$	D_n	Q_n
L	L	L
L	H	H
H	X	Z

FUNCTION TABLE, 74F126

INPUTS		OUTPUT
OE_n	D_n	Q_n
H	L	L
H	H	H
L	X	Z

H = High voltage level
L = Low voltage level
X = Don't care
Z = High impedance "off" state

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to +7.0	V
I_{IN}	Input current	-30 to +5	mA
V_{OUT}	Voltage applied to output in High output state	-0.5 to +V_{CC}	V
I_{OUT}	Current applied to output in Low output state	128	mA
T_A	Operating free-air temperature range	0 to +70	°C
T_{STG}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-15	mA
I_{OL}	Low-level output current			64	mA
T_A	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

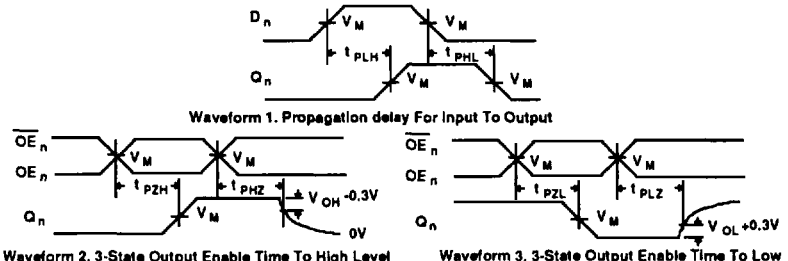
SYMBOL	PARAMETER			TEST CONDITIONS[1]			LIMITS			UNIT
							Min	Typ[2]	Max	
V_{OH}	High-level output voltage			V_{CC} = MIN, V_{IL} = MAX, V_{IH} = MIN	I_{OH}=-3mA	±10%V_{CC}	2.4			V
						±5%V_{CC}	2.7	3.3		V
					I_{OH}=-15mA	±10%V_{CC}	2.0			V
						±5%V_{CC}	2.0			V
V_{OL}	Low-level output voltage			V_{CC} = MIN, V_{IL} = MAX, V_{IH} = MIN	I_{OL}=MAX	±10%V_{CC}			0.55	V
						±5%V_{CC}		0.42	0.55	V
V_{IK}	Input clamp voltage			V_{CC} = MIN, I_I = I_{IK}				-0.73	-1.2	V
I_I	Input current at maximum Input voltage			V_{CC} =0.0V, V_I = 7.0V					100	µA
I_{IH}	High-level input current			V_{CC} = MAX, V_I = 2.7V					20	µA
I_I	Low-level input current			V_{CC} = MAX, V_I = 0.5V					-20	mA
I_{OZH}	Off-state output current, High-level voltage applied			V_{CC} = MAX, V_O= 2.7V					50	µA
I_{OZL}	Off-state output current, Low-level voltage applied			V_{CC} = MAX, V_O= 0.5V					-50	µA
I_{OS}	Short circuit output current[3]			V_{CC} = MAX			-100		-225	mA
I_{CC}	Supply current (total)	'F125	I_{CCH}	V_{CC} = MAX	$\overline{OE}_n$ = GND, D_n=4.5V			17	24	mA
			I_{CCL}		$\overline{OE}_n$ = D_n=GND			28	40	mA
			I_{CCZ}		$\overline{OE}_n$ = D_n=4.5V			25	35	mA
		'F126	I_{CCH}	V_{CC} = MAX	OE_n = D_n=4.5V			20	30	mA
			I_{CCL}		OE_n = 4.5V, D_n=GND			32	48	mA
			I_{CCZ}		OE_n = GND, D_n=4.5V			26	39	mA

NOTES:
1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_A = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

AC ELECTRICAL CHARACTERISTICS

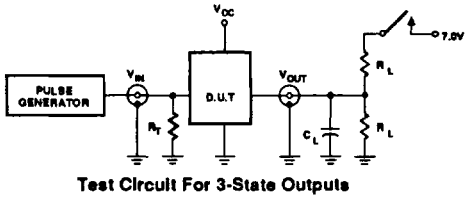
SYMBOL	PARAMETER		TEST CONDITION	LIMITS					UNIT
				T_A = +25°C, V_{CC} = 5V, C_L = 50pF, R_L = 500Ω			T_A = 0°C to +70°C, V_{CC} = 5V ±10%, C_L = 50pF, R_L = 500Ω		
				Min	Typ	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation delay D_n to Q_n	74F125	Waveform 1	2.0 3.0	4.0 5.5	6.0 7.5	2.0 3.0	6.5 8.0	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level		Waveform 2 Waveform 3	3.5 4.0	5.5 6.0	7.5 8.0	3.5 4.0	8.5 9.0	ns
t_{PHZ} t_{PLZ}	Output Disable time from High or Low level		Waveform 2 Waveform 3	1.5 1.5	3.5 3.5	5.0 5.5	1.5 1.5	6.0 6.0	ns
t_{PLH} t_{PHL}	Propagation delay D_n to Q_n	74F126	Waveform 1	2.0 3.0	4.0 5.5	6.5 8.0	2.0 3.0	7.0 8.5	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level		Waveform 2 Waveform 3	4.0 4.0	6.0 6.0	7.5 8.0	3.5 3.5	8.5 8.5	ns
t_{PHZ} t_{PLZ}	Output Disable time from High or Low level		Waveform 2 Waveform 3	2.0 3.0	4.5 5.5	6.5 7.5	2.0 3.0	7.5 8.0	ns

AC WAVEFORMS

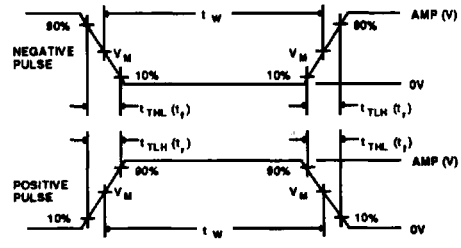


NOTE: For all waveforms, V_M = 1.5V.

TEST CIRCUIT AND WAVEFORMS



Test Circuit For 3-State Outputs



V_M = 1.5V

Input Pulse Definition

SWITCH POSITION

TEST	SWITCH
t_{PLZ}	closed
t_{PZL}	closed
All other	open

DEFINITIONS

R_L = Load resistor; see AC CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns